

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/664,500	YALOVSKY, MARK	
Examiner	Art Unit	
Maikhanh Nguyen	2176	

SEARCHED				
Class	Subclass	Date	Examiner	
715	530	5/5/2006	мк	
715	517,519	5/5/2006	MK	
715	520	5/5/2006	MK	
707	100	5/5/2006	MK	
Updated	above	11/15/2006	MK	
Updated	above	6/13/2007	MK	
Updated	above	1/17/2008	MK	
715	200 228	1/17/2008	MK	
715	234 244	1/17/2008	MK	
715	245 246	1/17/2008	MK	
715	251 253	1/17/2008	MK	
715	255 256	1/17/2008	MK	
715	273 856	1/17/2008	MK	
715	857 858	1/17/2008	MK	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
715	530	1/17/2008	MK	
715	525	1/17/2008	MK	
715	857	1/17/2008	MK	
USPAT -	USPGPub	1/17/2008	MK	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Name Search	5/5/2006	MK		
West Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB)	5/5/2006	MK		
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	11/15/2006	MK		
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	6/13/2007	МК		
Consulted with Primary William Bashore	1/14/2008	MK		
West Updated (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	1/17/2008	МК		
Interference Search	1/17/2008	мк		